

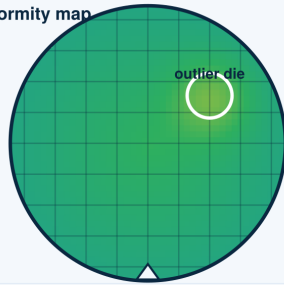
# Magnetic Metrology for Semiconductors

Test, calibrate & characterize **magnetic-sensor wafers**, **sputtering magnet systems** & **OEM test equipment**.

## Magnetic-Sensor Wafers

Hall / TMR / GMR

Wafer field-uniformity map



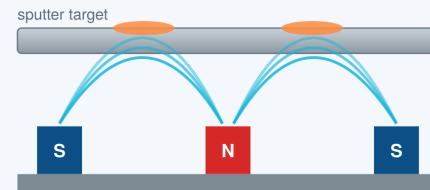
- Calibrate sensor dies in a known, traceable field
- Map field uniformity & flag outlier dies wafer-wide
- Verify applied field with 100 ppm teslameters

wafer-level test & calibration

## Sputtering Magnet Systems

PVD / magnetron

Magnetron cross-section



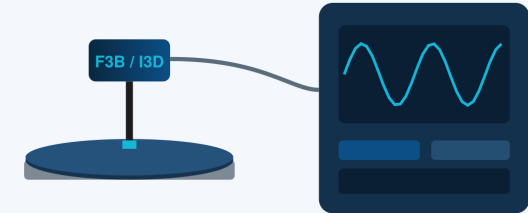
- Characterize magnet packs for uniform erosion
- Map field over the cathode — better target use
- QA magnet strength & balance before assembly

deposition uniformity & magnet QA

## OEM Test-Equipment

ATE / prober / handler

Embedded in your tester



- Integrate F3B / I3D analog transducers & probes
- In-situ field control in ATE, probers & handlers
- Compact probes, fast analog output, OEM support

drop-in OEM field measurement

## SENIS INSTRUMENTS FOR THE FAB

### F3B

3-axis analog transducer  
high f-bandwidth · OEM

### I3D

2-/3-axis transducer  
low-noise · high-resolution

### 3MH4

digital teslameter  
0.1% · 2  $\mu$ T · up to 9 T

### 3MH1-E

handheld teslameter  
battery · field & line QC

### Mappers & SENCAM

field mapping & camera  
wafer & magnet-pack maps